

Notice of References Cited	Application/Control No. 10/500,114	Applicant(s)/Patent Under Reexamination HAYAKAWA ET AL.	
	Examiner Vivian Chen	Art Unit 1773	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,294,264	09-2001	Piper et al.	428/475.8
	B	US-2002/0012756	01-2002	Kuckertz et al.	427/569
	C	US-6,055,505	04-2000	Elston, Mary B.	705/1
	D	US-5,466,498	11-1995	Forloni et al.	428/36.7
	E	US-4,563,316	01-1986	Isaka et al.	264/448
	F	US-4,717,516	01-1988	Isaka et al.	264/448
	G	US-4,888,223	12-1989	Sugimoto et al.	428/34.9
	H	US-5,302,402	04-1994	Dudenhoeffer et al.	426/129
	I	US-5,169,714	12-1992	Kondo et al.	428/331
	J	US-2002/0150780	10-2002	Ito et al.	428/480
	K	US-5,466,424	11-1995	Kusano et al.	422/186.05
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2001-233971	08-2001	JP	Taga et al	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.